	Application/Control No.	Applicant(s)/Patent under Reexamination
Search Notes	10/532,163	TAN ET AL.
	Examiner	**Art Unit**	
	Adrian L. Kennedy	2121	

SEARCHED			
Class	Subclass	Date	Examiner
706	45	7/15/2007	AK

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
IEEE	7/15/2007	AK
Google Scholar	7/15/2007	AK
Google	7/15/2007	AK
EAST	7/15/2007	AK
EAST	7/16/2007	AK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner